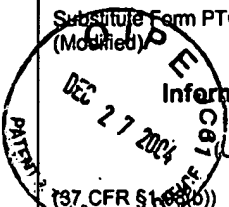


Substitute Form PTO-1449 (Modified)  Information Disclosure Statement by Applicant (Use several sheets if necessary)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 15758-003001	Application No. 10/630,543
	Applicant James Ma		
	Filing Date July 29, 2003	Group Art Unit 2819	

U.S. Patent Documents


Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
<i>JC</i>	AV	ICT paper entitled "PEEL™ Device Metastability"; date unknown but known to be before June 10, 2003; 3 pp
<i>JC</i>	AW	Semiati, et al., "Timing Measurements of Synchronization Circuits," VLSI Systems Research Center, Technion - Israel Institute of Technology, Haifa, Israel; May 2003; 10 pp
<i>JC</i>	AX	Varma, et al., "Metastability Reduction by Aperture Transformation," IBM India Research Laboratory, Centre for Applied Research Electronics, New Delhi, India; date unknown but known to be before June 10, 2003; 10pp

Examiner Signature 	Date Considered 2/1/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 15758-003001	Application No. <u>10630543</u> N/A
	Applicant James Ma		
	Filing Date July 29, 2003	Group Art Unit Unknown	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<u>gc</u>	AA	6,055,285	04/25/2000	Alston	—	—	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature <u>[Signature]</u>	Date Considered <u>9/14/04</u>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	